

**Search Notes**

Application/Control No.

10/028,919

Examiner

Thomas Sills

Applicant(s)/Patent under  
Reexamination

DEVAUX ET AL.

Art Unit

2633

**SEARCHED**

Class	Subclass	Date	Examiner
398	81	8/29/2005	J.D.
398	154	8/29/2005	J.D.
398	155	8/29/2005	
398	175	8/29/2005	
398	177	8/29/2005	
385	39	8/29/2005	

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search. Consulted Shi Li. Suggested searching classes 398/81, 175, and 385/39, IEEE database.	8/29/2005	J.D.
East Search. Consulted Shi Li. Suggested referring to foreign search report.	8/30/2005	J.D.
East Search. Consulted Shi Li on AWG optical devices.	9/6/2005	J.D.